

IFW

Docket No.: AR-R14

*IFW*  
MAY 24 2004  
I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date indicated below.

By: 

Date: May 21, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No. : 10/752,627 Confirmation No: 5973  
Applicant : Anton Rodi  
Filed : January 7, 2004  
Title : Measuring Device to Record Values, in Particular Angles or Linear Segments  
Art Unit : 2858  
Examiner : to be assigned  
  
Docket No. : AR-R14  
Customer No. : 24131

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner for Patents

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

United States Patent No. 5,414,516 (Morishita et al.), dated May 9, 1995, and corresponding German Published Non-Prosecuted Patent Application DE 44 19 050 A1, dated December 8, 1994;

United States Patent No. 5,485,407 (Ishimoto et al.), dated January 16, 1996;

United States Patent No. 5,943,639 (Tanaka et al.), dated August 24, 1999;

United States Patent Application Publication US 2002/0171418 A1 (Hinz et al.), dated November 21, 2002, and corresponding German Published Non-Prosecuted Patent Application DE 101 13 871 A1, dated September 26, 2002;

European Patent Application EP 0 394 942 A2 (Ishii et al.), dated October 31, 1990;

Tietze/Schenk: "Halbleitertechnik" [semiconductor technology], *Springer Verlag, Berlin, 12<sup>th</sup> ed., 2002, chapter 11, pp. 751-792, chapter 17, pp. 966-977, chapter 18, pp. 984-986, 899-1011, chapter 20, pp. 1069-1074, and chapter 21, pp. 1134-1138;*

European Search Report dated March 12, 2004.

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications, patents and/or publications, it is because no existing translation is readily available to the applicant. As per the Notice in 1273 OG 55 (August 5, 2003) no copies of any above-mentioned U.S. patents and U.S. patent application publications are submitted for any application filed after June 30, 2003.

Respectfully submitted,

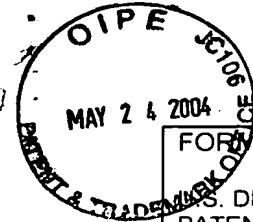
  
For Applicant

**Alfred K. Dassler**  
**52,794**

Date: May 21, 2004

Lerner And Greenberg, P.A.  
Post Office Box 2480  
Hollywood, FL 33022-2480  
Tel: (954) 925-1100  
Fax: (954) 925-1101

/bmb



<p>U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</p> <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))</p>	<p>Attorney Docket No.: AR-R14</p> <p>Applic. No. 10/752,627</p> <hr/> <p>Applicant Anton Rodi</p> <hr/> <p>Filing Date January 7, 2004</p> <p>Group Art Unit 2858</p>
--------------------------------------------------------------------------------------------------------------------------------------------------	----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------

## U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A	5,414,516	05/09/95	Morishita et al.			
	B	5,485,407	01/16/96	Ishimoto et al.			
	C	5,943,639	8/24/99	Tanaka et al.			
	D	2002/0171418 A1	11/21/02	Hinz et al.			
	E						
	F						
	G						
	H						
	I						

## FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES	NO
	J	44 19 050 A1	12/08/94	Germany				
	K	101 13 871 A1	09/26/02	Germany				
	L	0 394 942 A2	10/31/90	Europe				
	M							
	N							

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)**

	O	Tietze/Schenk: "Halbleitertechnik" [semiconductor technology], <i>Springer Verlag, Berlin, 12<sup>th</sup> ed., 2002</i> , chapter 11, pp. 751-792, chapter 17, pp. 966-977, chapter 18, pp. 984-986, 899-1011, chapter 20, pp. 1069-1074, and chapter 21, pp. 1134-1138
	P	

EXAMINER \_\_\_\_\_ DATE CONSIDERED \_\_\_\_\_  
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609;  
Draw line through citation if not in conformance and not considered. Include copy of this form with  
next communication to applicant.